



SEMiX® 3p

## Trench IGBT Modules

## SEMiX603GB12E4SiCp

## Features

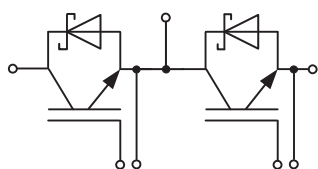
- With Silicon Carbide (SiC) Schottky diodes
- Homogeneous Si
- Trench = Trenchgate technology
- $V_{CE(sat)}$  with positive temperature coefficient
- Press-fit pins as auxiliary contacts
- Thermally optimized ceramic
- UL recognized, file no. E63532

## Typical Applications\*

- AC inverter drives
- UPS
- Renewable energy systems

## Remarks

- Product reliability results are valid for  $T_j = 150^\circ\text{C}$
- $V_{isol}$  between temperature sensor and power section is only 2500V
- $R_{G\ off}$  must be at least  $16\Omega$  in case  $V_{CC} \geq 900\text{V}$
- For storage and case temperature with TIM see document "TP(\*) SEMiX 3p"



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## Absolute Maximum Ratings

Symbol	Conditions	Values	Unit
<b>IGBT</b>			
$V_{CES}$	$T_j = 25^\circ\text{C}$	1200	V
$I_C$	$T_j = 175^\circ\text{C}$	$T_c = 25^\circ\text{C}$	1110
		$T_c = 80^\circ\text{C}$	853
$I_{Cnom}$		600	A
$I_{CRM}$	$I_{CRM} = 2 \times I_{Cnom}$	1200	A
$V_{GES}$		-20 ... 20	V
$t_{psc}$	$V_{CC} = 800\text{ V}$ $V_{GE} \leq 15\text{ V}$ $V_{CES} \leq 1200\text{ V}$	$T_j = 150^\circ\text{C}$	10
$T_j$		-40 ... 175	$^\circ\text{C}$
<b>Inverse diode</b>			
$V_{RRM}$	$T_j = 25^\circ\text{C}$	1200	V
$I_F$	$T_j = 175^\circ\text{C}$	$T_c = 25^\circ\text{C}$	404
		$T_c = 80^\circ\text{C}$	306
$I_{Fnom}$		300	A
$I_{FRM}$		900	A
$I_{FSM}$	$t_p = 8.3\text{ ms, sin } 180^\circ, T_j = 25^\circ\text{C}$	994	A
$T_j$		-40 ... 175	$^\circ\text{C}$
<b>Module</b>			
$I_{t(RMS)}$		600	A
$T_{stg}$	module without TIM	-40 ... 125	$^\circ\text{C}$
$V_{isol}$	AC sinus 50Hz, $t = 1\text{ min}$	4000	V

## Characteristics

Symbol	Conditions	min.	typ.	max.	Unit
<b>IGBT</b>					
$V_{CE(sat)}$	$I_C = 600\text{ A}$ $V_{GE} = 15\text{ V}$ chipelevel	$T_j = 25^\circ\text{C}$	1.80	2.05	V
		$T_j = 150^\circ\text{C}$	2.03	2.30	V
$V_{CE0}$	chipelevel	$T_j = 25^\circ\text{C}$	0.87	1.01	V
		$T_j = 150^\circ\text{C}$	0.77	0.9	V
$r_{CE}$	$V_{GE} = 15\text{ V}$ chipelevel	$T_j = 25^\circ\text{C}$	1.55	1.73	$\text{m}\Omega$
		$T_j = 150^\circ\text{C}$	2.1	2.3	$\text{m}\Omega$
$V_{GE(th)}$	$V_{GE} = V_{CE}, I_C = 22.2\text{ mA}$	5.3	5.8	6.3	V
$I_{CES}$	$V_{GE} = 0\text{ V}, V_{CE} = 1200\text{ V}, T_j = 25^\circ\text{C}$			5	mA
$C_{ies}$	$V_{CE} = 25\text{ V}$ $V_{GE} = 0\text{ V}$	$f = 1\text{ MHz}$	37.5		nF
$C_{oes}$		$f = 1\text{ MHz}$	2.31		nF
$C_{res}$		$f = 1\text{ MHz}$	2.04		nF
$Q_G$	$V_{GE} = -8\text{ V} \dots +15\text{ V}$		3450		nC
$R_{Gint}$	$T_j = 25^\circ\text{C}$		1.2		$\Omega$
$t_{d(on)}$	$V_{CC} = 600\text{ V}$	$T_j = 150^\circ\text{C}$	145		ns
$t_r$	$I_C = 600\text{ A}$	$T_j = 150^\circ\text{C}$	68		ns
$E_{on}$	$V_{GE} = +15/-15\text{ V}$	$T_j = 150^\circ\text{C}$	17		mJ
$t_{d(off)}$	$R_{G\ on} = 1.1\ \Omega$	$T_j = 150^\circ\text{C}$	520		ns
$t_f$	$R_{G\ off} = 1.1\ \Omega$	$T_j = 150^\circ\text{C}$	130		ns
$E_{off}$	$di/dt_{on} = 7550\text{ A}/\mu\text{s}$ $di/dt_{off} = 4220\text{ A}/\mu\text{s}$ $du/dt = 3450\text{ V}/\mu\text{s}$ $L_s = 21\text{ nH}$	$T_j = 150^\circ\text{C}$	72		mJ
$R_{th(j-c)}$	per IGBT			0.037	K/W
$R_{th(c-s)}$	per IGBT ( $\lambda_{grease} = 0.81\text{ W}/(\text{m}^2\text{K})$ )		0.035		K/W
$R_{th(c-s)}$	per IGBT, pre-applied phase change material		0.025		K/W



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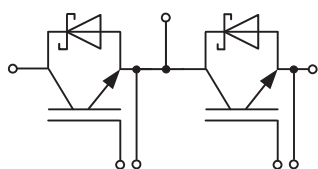
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Characteristics						
Symbol	Conditions		min.	typ.	max.	Unit
Inverse diode						
V <sub>F</sub> = V <sub>EC</sub>	I <sub>F</sub> = 300 A	T <sub>j</sub> = 25 °C		1.40	1.60	V
	V <sub>GE</sub> = 0 V chiplevel	T <sub>j</sub> = 150 °C		1.80	2.10	V
V <sub>F0</sub>	chiplevel	T <sub>j</sub> = 25 °C		0.95	1.05	V
		T <sub>j</sub> = 150 °C		0.80	0.90	V
r <sub>F</sub>	chiplevel	T <sub>j</sub> = 25 °C		1.50	1.83	mΩ
		T <sub>j</sub> = 150 °C		3.3	4.0	mΩ
C <sub>j</sub>	parallel to C <sub>oss</sub> , f = 1 MHz, V <sub>R</sub> = 800 V, T <sub>j</sub> = 25 °C			1.26		nF
Q <sub>c</sub>	V <sub>R</sub> = 600 V, di/dt <sub>off</sub> = 500 A/μs, T <sub>j</sub> = 25 °C			1.0		μC
R <sub>th(j-c)</sub>	per diode				0.14	K/W
R <sub>th(c-s)</sub>	per diode (λ <sub>grease</sub> =0.81 W/(m*K))			0.08		K/W
R <sub>th(c-s)</sub>	per Diode, pre-applied phase change material			0.065		K/W
Module						
L <sub>CE</sub>				20		nH
R <sub>CC'+EE'</sub>	measured per switch	T <sub>C</sub> = 25 °C		1.2		mΩ
		T <sub>C</sub> = 125 °C		1.65		mΩ
R <sub>th(c-s)1</sub>	calculated without thermal coupling, (λ <sub>grease</sub> =0.81 W/(m*K))			0.012		K/W
R <sub>th(c-s)2</sub>	including thermal coupling, Ts underneath module (λ <sub>grease</sub> =0.81 W/(m*K))			0.019		K/W
R <sub>th(c-s)2</sub>	including thermal coupling, Ts underneath module, pre-applied phase change material			0.015		K/W
M <sub>s</sub>	to heat sink (M5)		3		6	Nm
M <sub>t</sub>		to terminals (M6)	3		6	Nm
						Nm
w					350	g
Temperature Sensor						
R <sub>100</sub>	T <sub>C</sub> =100°C (R <sub>25</sub> =5 kΩ)			493 ± 5%		Ω
B <sub>100/125</sub>	R <sub>(T)</sub> =R <sub>100</sub> exp[B <sub>100/125</sub> (1/T-1/T <sub>100</sub> )]; T[K];			3550 ±2%		K



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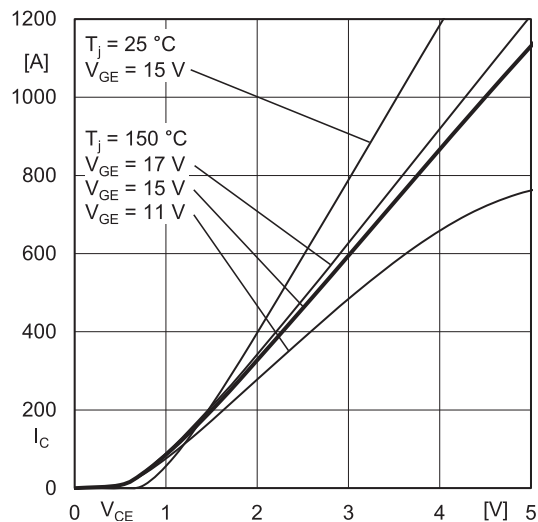
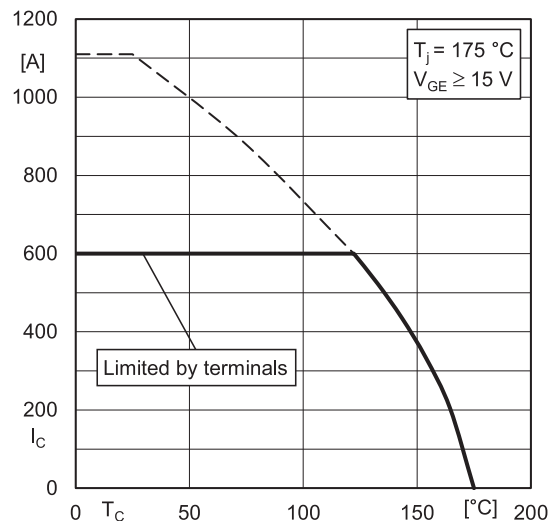
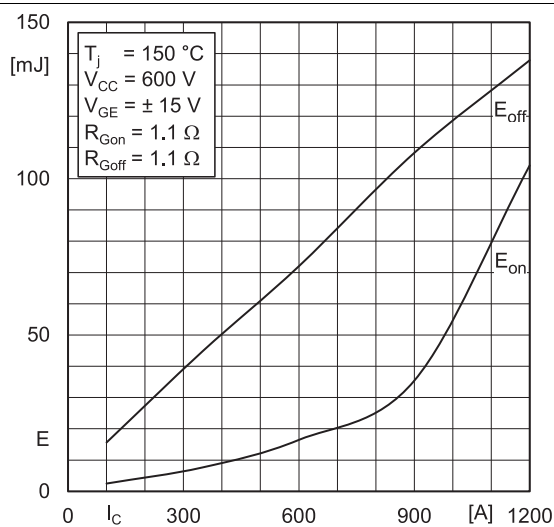
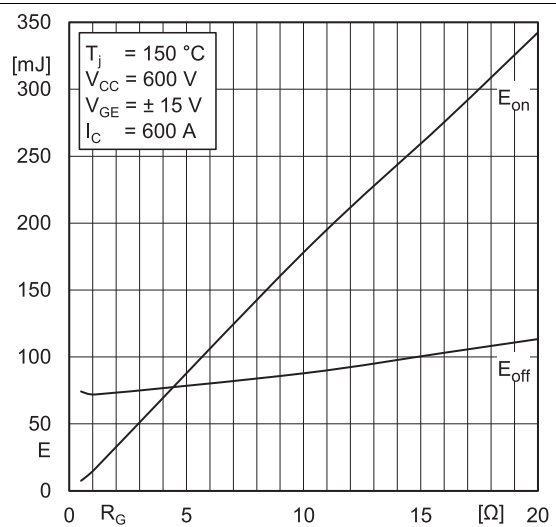
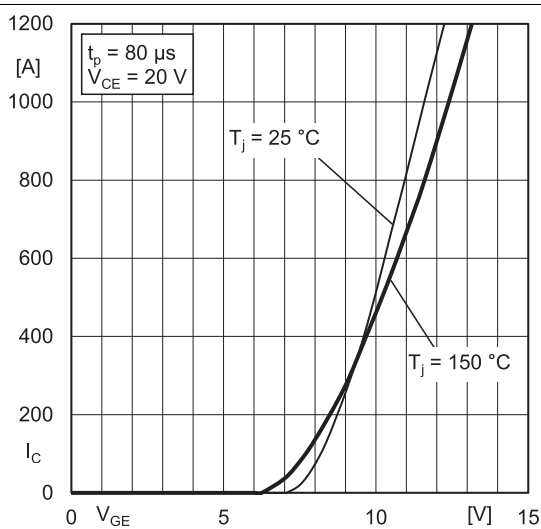
Fig. 1: Typ. output characteristic, inclusive  $R_{CC'+EE'}$ Fig. 2: Rated current vs. temperature  $I_C = f(T_C)$ Fig. 3: Typ. turn-on /-off energy =  $f(I_C)$ Fig. 4: Typ. turn-on /-off energy =  $f(R_G)$ 

Fig. 5: Typ. transfer characteristic

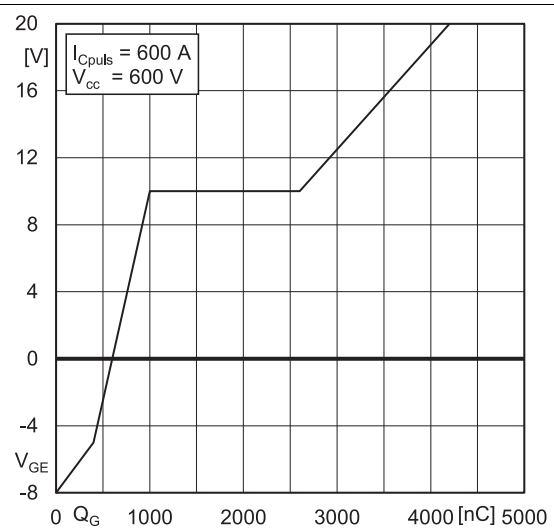
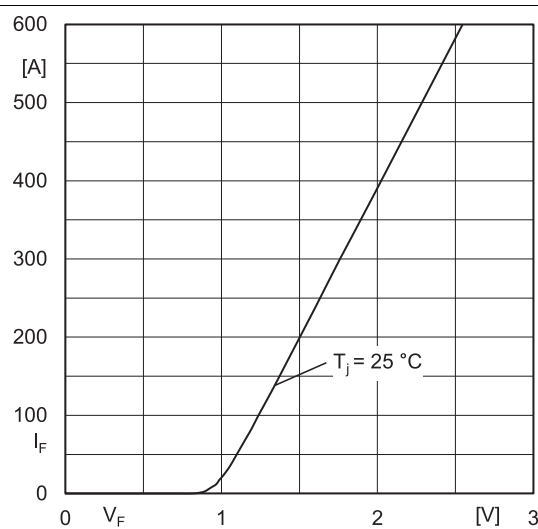
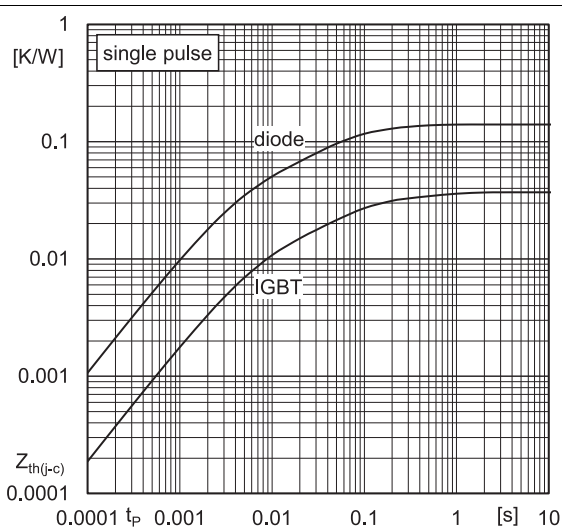
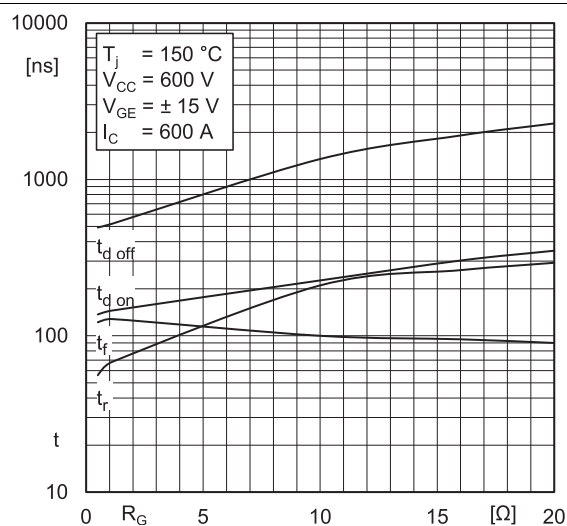
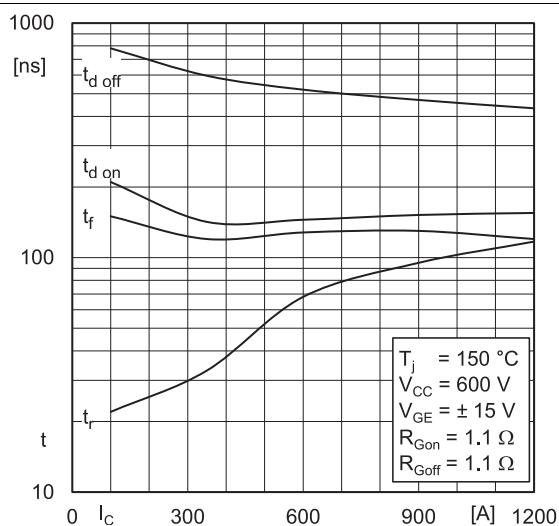


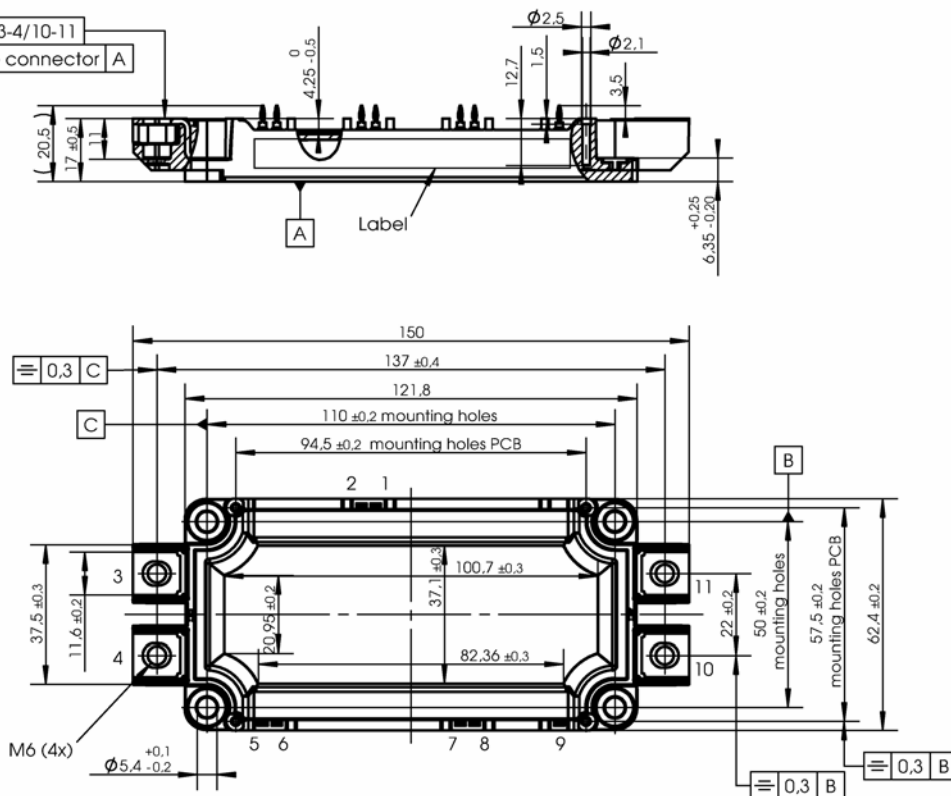
Fig. 6: Typ. gate charge characteristic



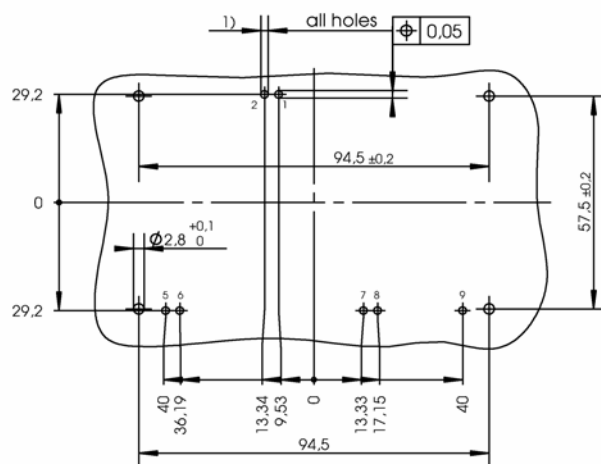
# SEMiX603GB12E4SiCp

Package outline

	0.3 connector 3-4/10-11
	0.2 each single connector A



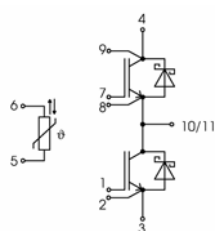
PCB drillhole pattern



1) PCB hole specification see Mounting Instructions SEMiX press-fit

Dimensions valid in mounted status

## SEMiX 3p



pinout

This is an electrostatic discharge sensitive device (ESDS), international standard IEC 60747-1, chapter IX.

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